

N-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^{a, e}	Q _g (Typ.)			
30	0.0021 at V _{GS} = 10 V	100	82 nC			
30	0.0030 at $V_{GS} = 4.5 \text{ V}$	90	02110			

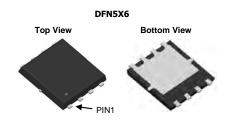
FEATURES

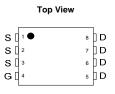
- DT-Trench Power MOSFET
- 100 % R_g and UIS Tested

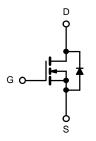


APPLICATIONS

- OR-ing
- Server







N-Channel MOSFET

Parameter	Symbol	Limit	Unit		
		V _{DS}	30	Jill	
Drain-Source Voltage		_		V	
Gate-Source Voltage	1	V _{GS}	± 20		
	$T_C = 25 ^{\circ}C$		100 ^{a, e}		
Continuous Drain Current (T _{.J} = 175 °C)	T _C = 70 °C	I-	90 ^e	A	
Continuous Diam Current (1) = 173 C)	T _A = 25 °C	I _D	33 ^{b, c}		
	T _A = 70 °C		29.8 ^{b, c}		
Pulsed Drain Current		I _{DM}	380		
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	36		
Single Pulse Avalanche Energy	L = 0.1 IIII	E _{AS}	64.8	mJ	
Continuous Course Drain Diada Current	T _C = 25 °C	I.	90 ^{a, e}	Α	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	3.13 ^{b, c}		
	T _C = 25 °C		250 ^a	w	
Marijasum Davum Disainatian	T _C = 70 °C	В	175		
Maximum Power Dissipation	T _A = 25 °C	P _D	3.75 ^{b, c}		
	T _A = 70 °C		2.63 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	32	40	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.5	0.6	°C/VV	

Notes:

- a. Based on T_C = 25 °C. b. Surface mounted on 1" x 1" FR4 board.
- d. Maximum under steady state conditions is 90 °C/W.
- e. Calculated based on maximum junction temperature. Package limitation current is 90 A.



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Parameter	Symbol	Test Conditions	Min .	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			>	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		35		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	1 _D = 200 μΑ		- 7.5			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1		3	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zoro Coto Voltago Drain Current	1	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1		
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10) µA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	90			Α	
D : 0	В	$V_{GS} = 10 \text{ V}, I_D = 32 \text{ A}$		0.0021	0.0023	Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 29 \text{ A}$		0.0030	0.0033		
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 32 A		160		S	
Dynamic ^b							
Input Capacitance	C _{iss}			2765		pF	
Output Capacitance	C _{oss}	V_{DS} = 12.5 V, V_{GS} = 0 V, f = 1 MHz		1725			
Reverse Transfer Capacitance	C _{rss}			970			
Total Gate Charge	Q _g	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 32 \text{ A}$		171	257		
				81.5	123	nC	
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 29 \text{ A}$		34			
Gate-Drain Charge	Q _{gd}			29			
Gate Resistance	R _g	f = 1 MHz		1.4	2.1	Ω	
Turn-On Delay Time	t _{d(on)}			18	27		
Rise Time	t _r	$V_{DD} = 15 \text{ V}, R_{L} = 0.555 \Omega$		11	17		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 27$ A, $V_{GEN}=10$ V, $R_g=1$ Ω		70	105		
Fall Time	t _f			10	15		
Turn-On Delay Time	t _{d(on)}			55	83	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.625 Ω		180	270		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 24$ A, V_{GEN} = 4.5 V, R_g = 1 Ω		55	83		
Fall Time	t _f			12	18		
Drain-Source Body Diode Characteristic	s		I.	1			
Continuous Source-Drain Diode Current	I _S	$T_C = 25 ^{\circ}C$			100	٨	
Pulse Diode Forward Current ^a	I _{SM}				380	Α	
Body Diode Voltage	V _{SD}	I _S = 22 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			52	78	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	1 20 A di/dt 100 A/vo T 25 °C		70.2	105	nC	
Reverse Recovery Fall Time	t _a	$I_F = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		27			
Reverse Recovery Rise Time t _b				25		ns	

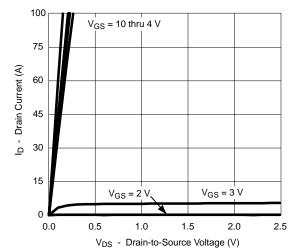
Notes:

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

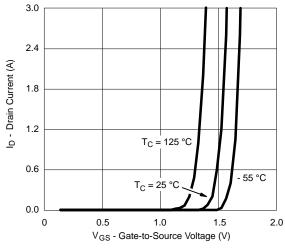
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



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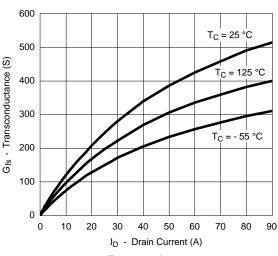


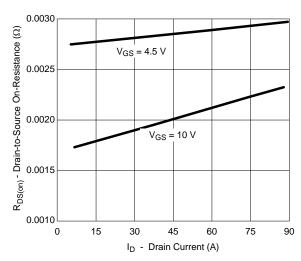
Din-Tek SEMICONDUCTOR





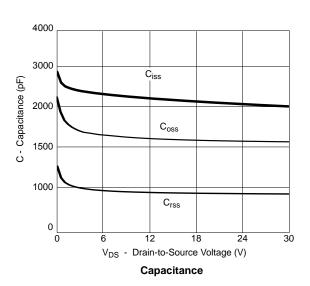


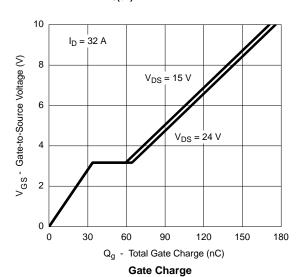




Transconductance

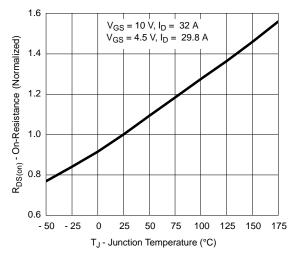
R_{DS(on)} vs. Drain Current



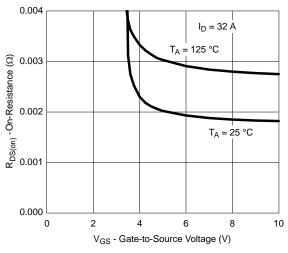




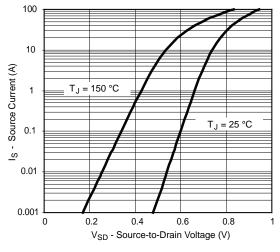
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



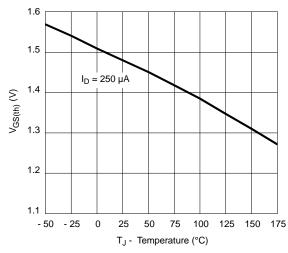
On-Resistance vs. Junction Temperature



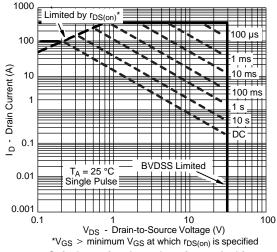
 $R_{DS(on)}$ vs. V_{GS} vs. Temperature



Forward Diode Voltage vs. Temperature



Threshold Voltage

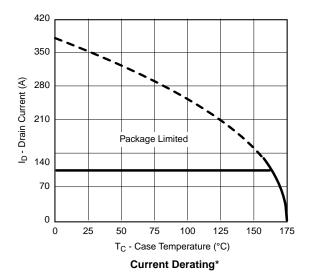


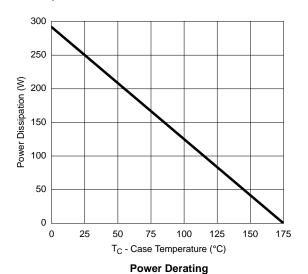
Safe Operating Area, Junction-to-Ambient



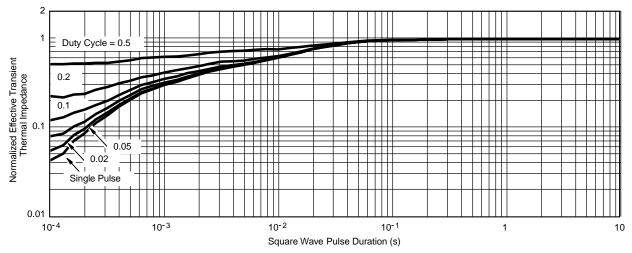


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





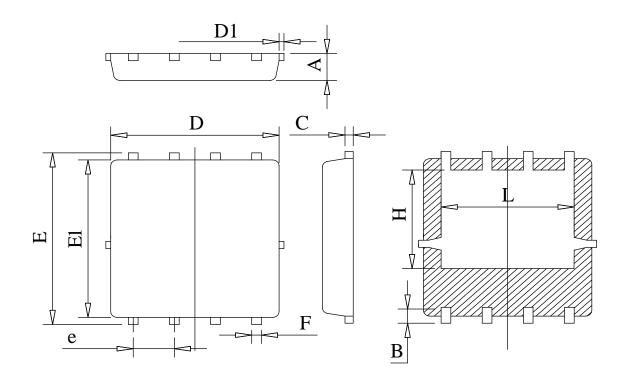
* The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Normalized Thermal Transient Impedance, Junction-to-Case



DFN5X6-8L PACKAGE OUTLINE



COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)

Unit: mm

Symbol	Min	Тур	Max
A	0.78	0.95	1.12
В	0.45	0.58	0.78
С	0.18	0.254	0.36
D	4.70	5.20	5.45
D1			0.18
Е	5.85	6.05	6.25
E1	5.38	5.55	5.98
e	1.15	1.27	1.40
F	0.18	0.30	0.52
Н	3.25	3.47	3.70
L	3.75	4.00	4.25





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